BS78 (with/without origin)

High-speed and high-resolution, while maintaining stable, ultraprecision measuring. Ideal for precision stages, semiconductor inspection/manufacturing systems, and ultraprecision processing machines.

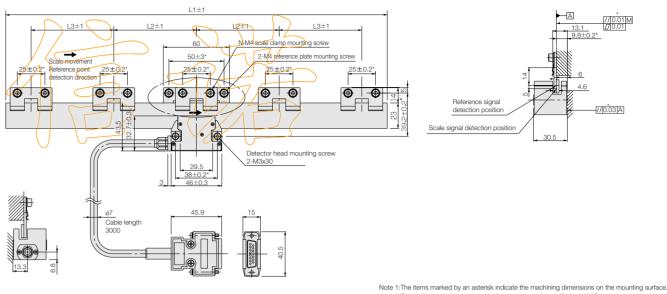


- High-resolution scale with signal wavelength of approx. 138nm, outperforming light wave interferometer systems
- High stability, unaffected by humidity, air pressure and air disturbances
- Reference point accuracy: ±0.1μm
- Scale accuracy: ±0.04μm or better (measuring length: 40 mm)
- Completely non-contact design Return error is virtually eliminated.
- Special non-magnetic and vacuum-compatible models available
- Using low expansion glass: -0.7 x 10⁻⁶/°C (measuring length: 10 to 420 mm)

R: with reference point; RS: high accuracy with reference point N: without reference point; NS: high accuracy without reference point

External Dimensions

● BS78-xxxN(NS)(measuring length:40/120/170/220/370/420)



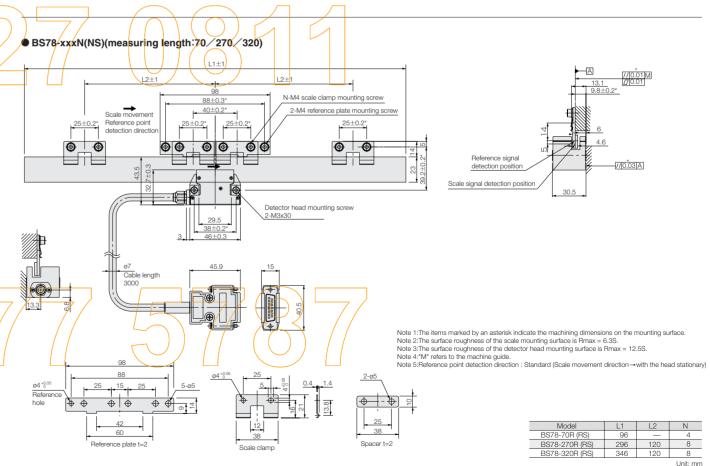
Note 4:"M" refers to the machine guide.

Note 2:The surface roughness of the scale mounting surface is Rmax = 6.3S.

Note 3:The surface roughness of the detector head mounting surface is Rmax = 12.5S.

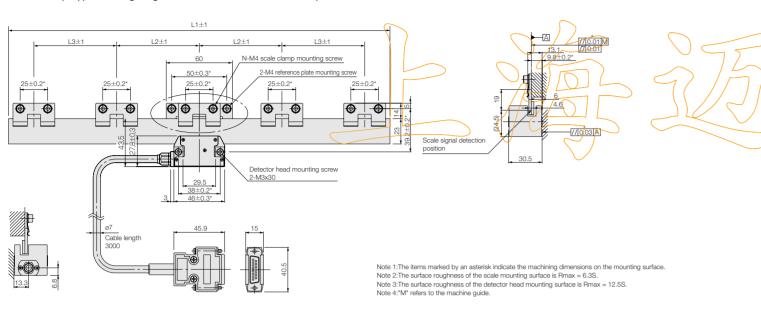
Note 5:Reference point detection direction : Standard (Scale movement direction → with the head stationary)

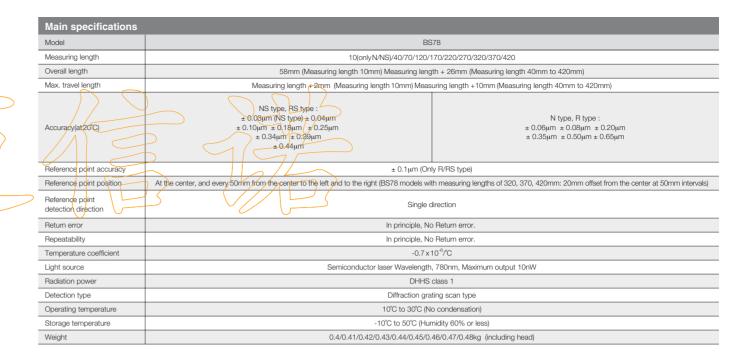
Model	L1	L2	L3	N
BS78-40R (RS)	66	_	_	2
BS78-120R (RS)	146	50	_	6
BS78-170R (RS)	196	75	_	6
BS78-220R (RS)	246	100	_	6
BS78-370R (RS)	396	75	75	10
BS78-420R (RS)	446	100	100	10

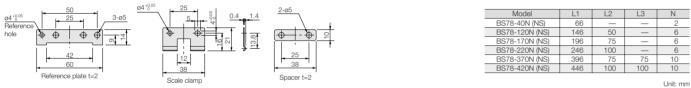


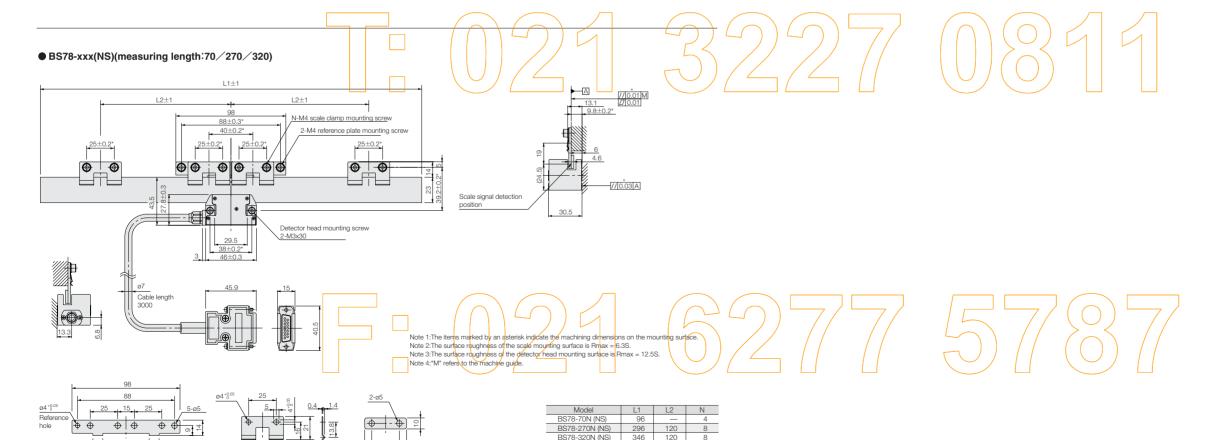
External Dimensions

● BS78-xxx(NS)(measuring length:40/120/170/220/370/420)









12

Unit: mm